

VE320 Introduction of Semiconductor Device  
Homework 5  
Due Date: July 11

5.1 An abrupt silicon pn junction at zero bias has dopant concentrations of  $N_a = 10^{17} \text{ cm}^{-3}$  and  $N_d = 5 \times 10^{15} \text{ cm}^{-3}$ .  $T = 300 \text{ K}$ .

- (a) Calculate the Fermi level on each side of the junction with respect to the intrinsic Fermi level.
- (b) Sketch the equilibrium energy-band diagram for the junction and determine  $V_{bi}$  from the diagram and the results of part (a).
- (c) Calculate  $V_{bi}$  using Equation (7.10), and compare the results to part (b).
- (d) Determine  $x_n$ ,  $x_p$ , and the peak electric field for this junction

5.2 A silicon pn junction in thermal equilibrium at  $T = 300 \text{ K}$  is doped such that  $E_F - E_{Fi} = 0.365 \text{ eV}$  in the n region and  $E_{Fi} - E_F = 0.330 \text{ eV}$  in the p region.

- (a) Sketch the energy-band diagram for the pn junction.
- (b) Find the impurity doping concentration in each region.
- (c) Determine  $V_{bi}$ .

5.3 (a) Consider a uniformly doped silicon pn junction at  $T = 300 \text{ K}$ . At zero bias, 25 percent of the total space charge region is in the n-region. The built-in potential barrier is  $V_{bi} = 0.710 \text{ V}$ . Determine (i)  $N_a$ , (ii)  $N_d$ , (iii)  $x_n$ , (iv)  $x_p$ , and (v)  $E_{\max}$ .

5.4 An “isotype” step junction is one in which the same impurity type doping changes from one concentration value to another value. An n-n isotype doping profile is shown in Figure 1. (a) Sketch the thermal equilibrium energy-band diagram of the isotype junction. (b) Using the energy-band diagram, determine the built-in potential barrier. (c) Discuss the charge distribution through the junction

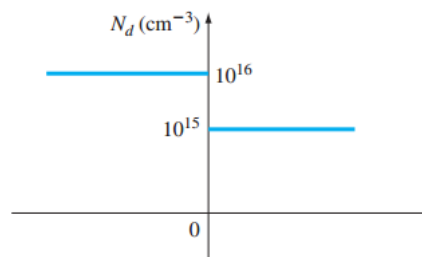


Figure 1

5.5 An abrupt silicon pn junction at  $T = 300 \text{ K}$  has impurity doping concentrations of  $N_a = 5 \times 10^{16} \text{ cm}^{-3}$  and  $N_d = 10^{15} \text{ cm}^{-3}$ . Calculate (a)  $V_{bi}$ , (b)  $W$  at (i)  $V_R = 0$  and (ii)  $V_R = 5 \text{ V}$ , and (c)  $|E_{\max}|$  at (i)  $V_R = 0$  and (ii)  $V_R = 5 \text{ V}$ .

5.6 An ideal one-sided silicon  $p^+n$  junction at  $T = 300$  K is uniformly doped on both sides of the metallurgical junction. It is found that the doping relation is  $N_a = 80N_d$  and the built-in potential barrier is  $V_{bi} = 0.740$  V. A reverse-biased voltage of  $V_R = 10$  V is applied. Determine (a)  $N_a, N_d$ , (b)  $x_p, x_n$ , (c)  $|E_{max}|$ , and (d)  $C_j$ .

5.7 Consider a silicon pn junction with the doping profile shown in Figure 2.  $T = 300$  K. (a) Calculate the applied reverse-biased voltage required so that the space charge region extends entirely through the p region. (b) Determine the space charge width into the  $n^+$  region with the reverse-biased voltage calculated in part (a). (c) Calculate the peak electric field for this applied voltage. (You can ignore the influence of  $p^+$ )

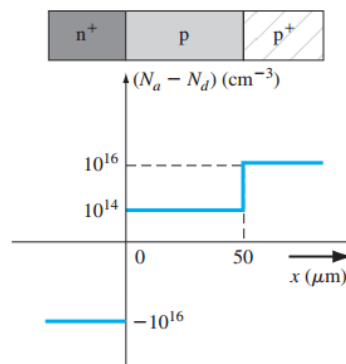


Figure 2